

## NOTICE OF REFERENCES CITED

APPLICANT(S)

Chen et al.

## U.S. PATENT DOCUMENTS

		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
A	5	012439	Apr. 30, 1991	Nash et al.	364	766	
B	4	891780	Jan. 2, 1990	Miyoshi	364	766	
C	5	297073	May. 22, 1994	Davidian	364	766	
D	5	097435	Mar. 17, 1992	Takahashi	364	766	
E	5	34122	Aug. 23, 1996	Fettweis et al.	364	766	
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUB-CLASS	PERTINENT SHTS. DWG.	PP. SPEC.
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M									
N									
O									
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Q									

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

Emmanuel Hoise

DATE

08/26/96

\* A copy of this reference is not being furnished with this office action.  
(See Manual of Patent Examining Procedure, section 707.05 (a).)